

High Temperature Silicon Carbide Power Schottky Diode

| | | |
|----------------------------------|---|-------|
| V_{RRM} | = | 650 V |
| $I_F @ 25\text{ }^\circ\text{C}$ | = | 30 A |
| Q_C | = | 66 nC |

Features

- 650 V Schottky rectifier
- 250 °C maximum operating temperature
- Zero reverse recovery charge
- Superior surge current capability
- Positive temperature coefficient of V_F
- Temperature independent switching behavior
- Lowest figure of merit Q_C/I_F
- Available screened to Mil-PRF-19500



Die Size = 2.95 mm x 2.95 mm

Advantages

- High temperature operation
- Improved circuit efficiency (Lower overall cost)
- Low switching losses
- Ease of paralleling devices without thermal runaway
- Smaller heat sink requirements
- Industry's lowest reverse recovery charge
- Industry's lowest device capacitance
- Ideal for output switching of power supplies
- Best in class reverse leakage current at operating temperature

Applications

- Down Hole Oil Drilling
- Geothermal Instrumentation
- Solenoid Actuators
- General Purpose High-Temperature Switching
- Amplifiers
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)

Maximum Ratings at $T_j = 250\text{ }^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Values | Unit |
|------------------------------------------------------|----------------|------------------------------------------------------------------|------------|------------------|
| Repetitive peak reverse voltage | V_{RRM} | | 650 | V |
| Continuous forward current | I_F | $T_C = 25\text{ }^\circ\text{C}$, $R_{thJC} = 1.08$ | 30 | A |
| Continuous forward current | I_F | $T_C \leq 225\text{ }^\circ\text{C}$, $R_{thJC} = 1.08$ | 9.4 | A |
| RMS forward current | $I_{F(RMS)}$ | $T_C \leq 225\text{ }^\circ\text{C}$, $R_{thJC} = 1.08$ | 16 | A |
| Surge non-repetitive forward current, Half Sine Wave | $I_{F,SM}$ | $T_C = 25\text{ }^\circ\text{C}$, $t_p = 10\text{ ms}$ | 140 | A |
| Non-repetitive peak forward current | $I_{F,max}$ | $T_C = 25\text{ }^\circ\text{C}$, $t_p = 10\text{ }\mu\text{s}$ | 650 | A |
| I^2t value | $\int i^2 dt$ | $T_C = 25\text{ }^\circ\text{C}$, $t_p = 10\text{ ms}$ | 98 | A ² S |
| Power dissipation | P_{tot} | $T_C = 25\text{ }^\circ\text{C}$, $R_{thJC} = 1.08$ | 208 | W |
| Operating and storage temperature | T_j, T_{sig} | | -55 to 250 | °C |

Electrical Characteristics at $T_j = 250\text{ }^\circ\text{C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Values | | | Unit |
|-------------------------|--------|---------------------------------------------------------------------------------------------------|--------|------|------|---------------|
| | | | min. | typ. | max. | |
| Diode forward voltage | V_F | $I_F = 10\text{ A}$, $T_j = 25\text{ }^\circ\text{C}$ | | 1.3 | | V |
| | | $I_F = 10\text{ A}$, $T_j = 210\text{ }^\circ\text{C}$ | | 1.8 | | |
| Reverse current | I_R | $V_R = 650\text{ V}$, $T_j = 25\text{ }^\circ\text{C}$ | | 1 | 5 | μA |
| | | $V_R = 650\text{ V}$, $T_j = 250\text{ }^\circ\text{C}$ | | 50 | 200 | |
| Total capacitive charge | Q_C | $I_F \leq I_{F,MAX}$ $dI_F/dt = 200\text{ A}/\mu\text{s}$ $T_j = 210\text{ }^\circ\text{C}$ | | 66 | | nC |
| Switching time | t_s | $V_R = 400\text{ V}$ | | < 49 | | ns |
| | | $V_R = 400\text{ V}$ | | < 49 | | |
| Total capacitance | C | $V_R = 1\text{ V}$, $f = 1\text{ MHz}$, $T_j = 25\text{ }^\circ\text{C}$ | | 1107 | | pF |
| | | $V_R = 400\text{ V}$, $f = 1\text{ MHz}$, $T_j = 25\text{ }^\circ\text{C}$ | | 103 | | |
| | | $V_R = 650\text{ V}$, $f = 1\text{ MHz}$, $T_j = 25\text{ }^\circ\text{C}$ | | 99 | | |

Figures:

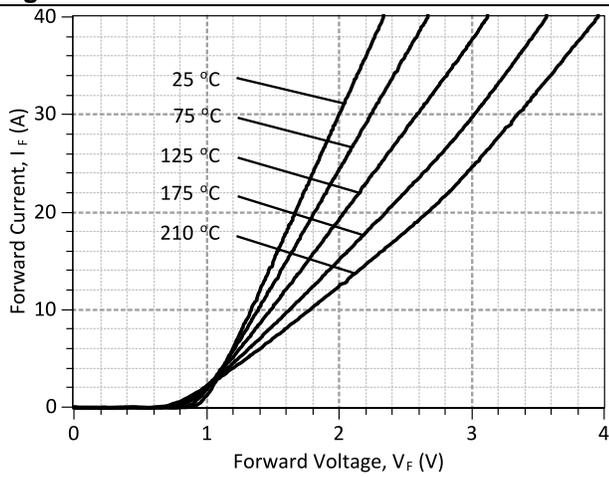


Figure 1: Typical Forward Characteristics

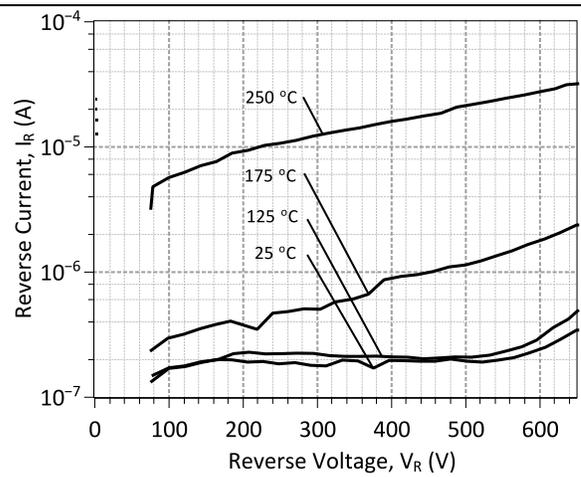


Figure 2: Typical Reverse Characteristics

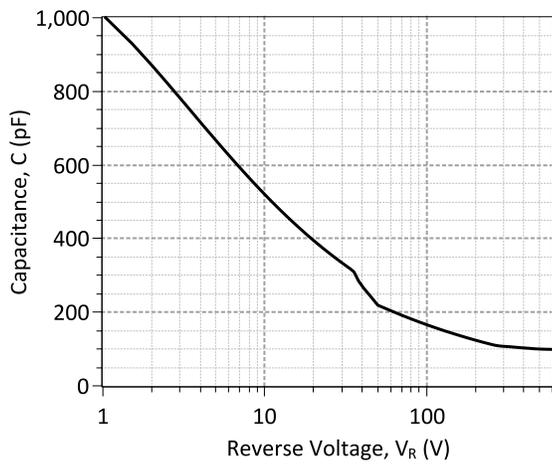


Figure 3: Typical Junction Capacitance vs Reverse Voltage Characteristics

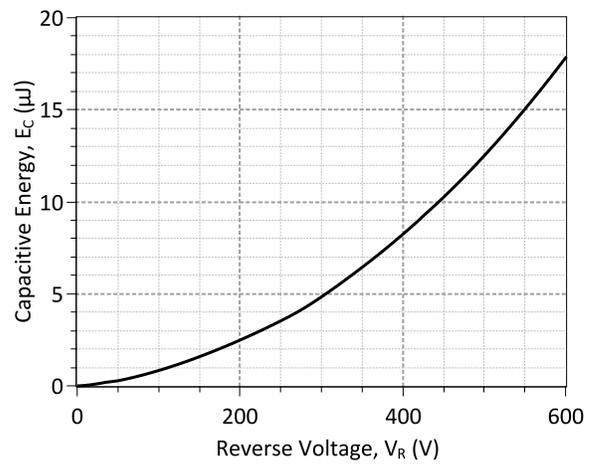
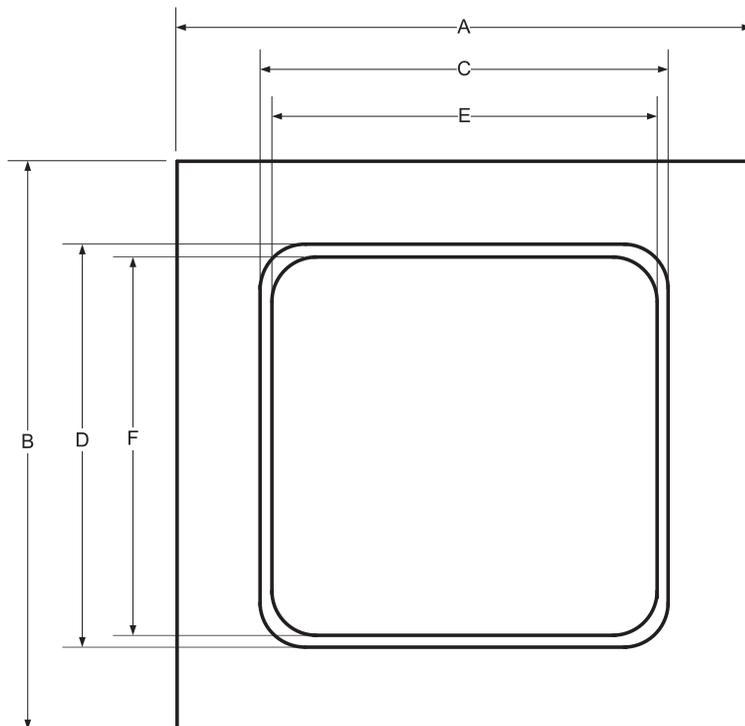


Figure 4: Typical Capacitive Energy vs Reverse Voltage Characteristics

Mechanical Parameters

| | | |
|---------------------------------|------------------------------------------------------------------------------------------------|-----------------|
| Die Dimensions | 2.95 x 2.95 | mm ² |
| Anode pad size | 2.69 x 2.69 | |
| Die Area total / active | 8.70/7.02 | |
| Die Thickness | 360 | μm |
| Wafer Size | 100 | mm |
| Flat Position | 0 | deg |
| Die Frontside Passivation | Polyimide | |
| Anode Pad Metallization | 400 nm Ni + 200 nm Au | |
| Backside Cathode Metallization | 400 nm Ni + 200 nm Au | |
| Die Attach | Electrically conductive glue or solder | |
| Wire Bond | Au ≤ 76 μm | |
| Reject ink dot size | Φ ≥ 0.3 mm | |
| Recommended storage environment | Store in original container, in dry nitrogen, < 6 months at an ambient temperature of 23 °C | |

Chip Dimensions:



| | | |
|----------------------|--------|------|
| DIE | A [mm] | 2.95 |
| | B [mm] | 2.95 |
| METAL | C [mm] | 2.69 |
| | D [mm] | 2.69 |
| WIRE BONDABLE | E [mm] | 2.65 |
| | F [mm] | 2.65 |

Revision History

| Date | Revision | Comments | Supersedes |
|------------|----------|--------------------------------|------------|
| 2015/02/09 | 1 | Inserted Mechanical Parameters | |
| 2012/04/03 | 0 | Initial release | |

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SPICE Model Parameters

This is a secure document. Please copy this code from the SPICE model PDF file on our website (http://www.genesicsemi.com/images/hit_sic/baredie/schottky/GB20SHT06-CAU_SPICE.pdf) into LTSPICE (version 4) software for simulation of the GB20SHT06-CAU.

```
*      MODEL OF GeneSiC Semiconductor Inc.
*
*      $Revision:  1.0          $
*      $Date:    05-SEP-2013    $
*
*      GeneSiC Semiconductor Inc.
*      43670 Trade Center Place Ste. 155
*      Dulles, VA 20166
*
*      COPYRIGHT (C) 2013 GeneSiC Semiconductor Inc.
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*      These models are provided "AS IS, WHERE IS, AND WITH NO WARRANTY
*      OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED
*      TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
*      PARTICULAR PURPOSE."
*      Models accurate up to 2 times rated drain current.
*
*      Start of GB20SHT06-CAU SPICE Model
*
.SUBCKT GB20SHT06 ANODE KATHODE
D1 ANODE KATHODE GB20SHT06_25C; Call the Schottky Diode Model
D2 ANODE KATHODE GB20SHT06_PIN; Call the PiN Diode Model
.MODEL GB20SHT06_25C D
+ IS      8.46E-17          RS      0.0319
+ N       1                IKF     1000
+ EG      1.2              XTI     3
+ TRS1    0.0038          TRS2    3.00E-05
+ CJO     1.26E-09        VJ      0.438
+ M       1.5278          FC      0.5
+ TT      1.00E-10        BV      650
+ IBV     1.00E-03        VPK     650
+ IAVE    20              TYPE    SiC_Schottky
+ MFG     GeneSiC_Semiconductor
.MODEL GB20SHT06_PIN D
+ IS      2.77E-10          RS      0.086693
+ N       3.3505          IKF     3.67E-06
+ EG      3.23           XTI     -10
+ FC      0.5            TT      0
+ BV      650            IBV     1.00E-03
+ VPK     650            IAVE    20
+ TYPE    SiC_PiN
.ENDS
*
*      End of GB20SHT06-CAU SPICE Model
```

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